



Call for Posters

International Test Conference is the world's premier event dedicated to the electronic test of devices, boards and systems—covering the complete cycle from design verification, design-for-test, silicon debug, manufacturing test, system test, diagnosis, failure analysis and back to process and design improvement. At ITC, test and design professionals can confront the challenges the industry faces, and learn how these challenges are being addressed by the combined efforts of academia, design tool and equipment suppliers, designers, and test engineers.

ITC, the cornerstone of the Test Week™ event, offers a wide variety of technical activities targeted at test and design theoreticians and practitioners, including: formal paper sessions, tutorials, panel sessions, case studies, a lecture series, commercial exhibits and presentations, and a host of ancillary professional meetings.

Posters – A different way to participate in ITC

Unlike presentations, poster sessions are very interactive. It is a chance to create a discussion with industry experts around your work and a perfect opportunity to get feedback on new ideas, and late breaking/interesting results without having to write a full paper. Acceptance as a poster does not preclude submission of a more complete treatment as an ITC paper in 2010. Posters will be a part of the ITC **Texas Beer Blast Reception** after the last session on Tuesday, November 3. Posters should be a single 20" by 30" sheet of poster board and a presentation on a presenter-supplied laptop. Presenters can also make a five-minute summary presentation of their material at a special session on Tuesday afternoon. The poster session was a huge success in 2008. You can be part of the success in 2009 by submitting a poster proposal.

Submissions must include:

- Title of poster.
- Name, affiliation, mailing address, e-mail address, phone and fax number of each author.
- Designation of the presenter(s). ITC will communicate with the presenter.
- One or two topic(s) from the topic list, or a description of your topic.
- An electronic copy of a one page summary of the poster, in PDF format. If the poster is accepted, this summary will be included in the ITC Proceedings CD.
- An abstract of 35 words or less.

Please note that the submission deadline is firm.

Submission Deadline: July 17, 2009
Author Notification: August 10, 2009

All one-page submissions must be in electronic format. Prospective authors should read the detailed instructions regarding formats and submission requirements for posters which are available on the ITC Web site at:

<http://www.itctestweek.org>

For further information, check the ITC Web page or contact:

International Test Conference,
Washington, DC, USA
Tel: +1 202.973.8665 Fax: +1 202.331.0111
E-mail: itc@courtesyassoc.com

Program Chair

Bill Eklow, Cisco Systems, Inc.
E-mail: beklow@cisco.com

ITC invites submissions on the latest techniques for testing and diagnosing ICs, boards and systems.

Conference Focus Topics

Adaptive Test
BIST or Embedded Test—Chip and Board
Bring-up Test and Silicon Debug
Design and Test for Reliability
Experiments and Case Studies
High-Speed Digital Test
Low-Cost Test/ATE
On-Chip Test Compression
Online Test
RF Testing
Test Data Analysis
Test for Nanometer Technologies
Test Resource Partitioning

Hot Topics

Board and System Test
Defect-based Testing
High-Speed I/O Test
Innovative Industrial Test Practice
Power Issues in Test
Test and Design for Manufacturability
Volume Diagnosis and Yield Learning

Regular Topics:

ATE Hardware and Software
ATPG, Test Synthesis
Boundary-Scan
Design-for-Test: Chip, Board and System
Economics of Test
FPGA Test
I_{DDQ} and Current Test
Interface Issues
Loadboard Design and Simulation
MCM and KGD Test
Memory Test
Microprocessor Test
Mixed-Signal and Analog Test
Multisite Test
Production Test Automation
System-on-Chip Test
System-in-Package Test
Test Standards
Test Effectiveness
Wafer Probe